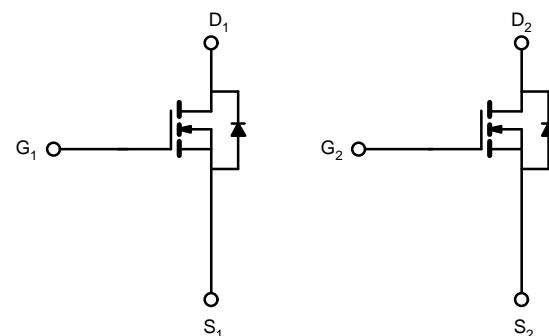
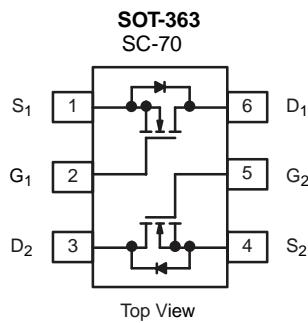


Dual N-Channel 20 V (D-S) MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)
20	0.086 at V _{GS} = 4.5 V	2.6 ^a	5.0 nC
	0.110 at V _{GS} = 2.5 V	2.5 ^a	
	0.180 at V _{GS} = 1.8 V	2.3 ^a	

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- Typical ESD Protection 2100 V HBM
- Compliant to RoHS Directive 2002/95/EC



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C, unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	20	V
Gate-Source Voltage	V _{GS}	± 12	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	2.6 ^a	A
	T _C = 70 °C	2.2 ^a	
	T _A = 25 °C	2.3 ^{a, b, c}	
	T _A = 70 °C	1.8 ^{b, c}	
Pulsed Drain Current	I _{DM}	8	
Continuous Source-Drain Diode Current	T _C = 25 °C	2.3	W
	T _A = 25 °C	2.10 ^{b, c}	
Maximum Power Dissipation	T _C = 25 °C	2.70	
	T _C = 70 °C	1.70	
	T _A = 25 °C	1.5 ^{b, c}	
	T _A = 70 °C	1.0 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	130	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	80	
Maximum under steady state conditions is 220 °C/W.			100	

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 220 °C/W.

SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)

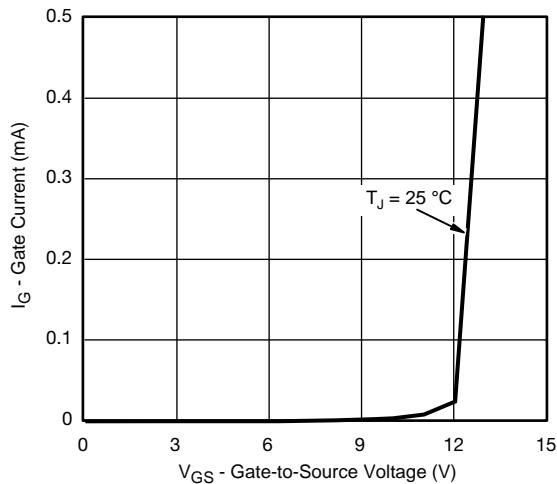
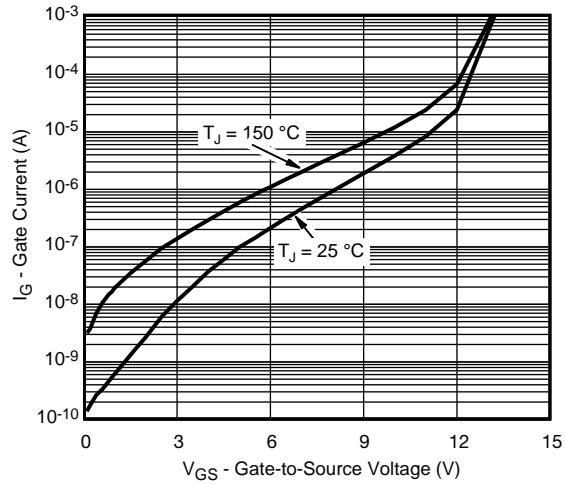
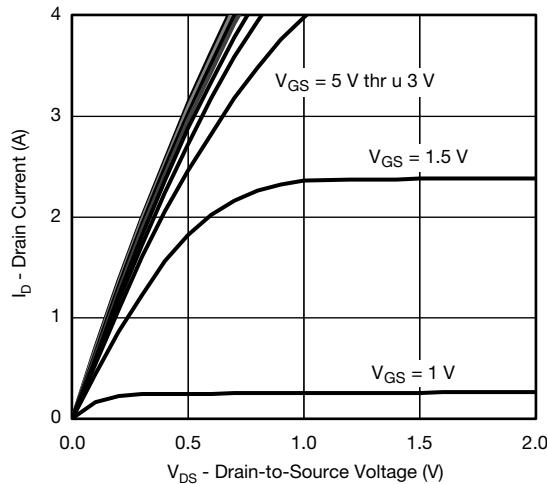
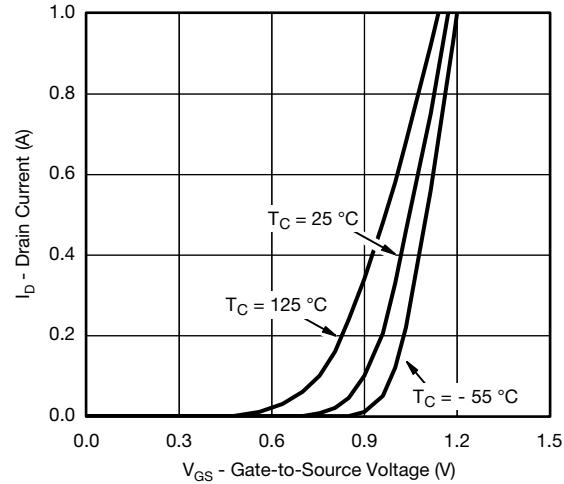
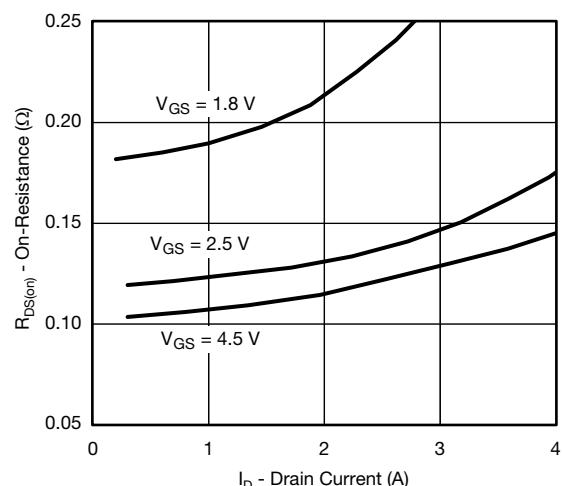
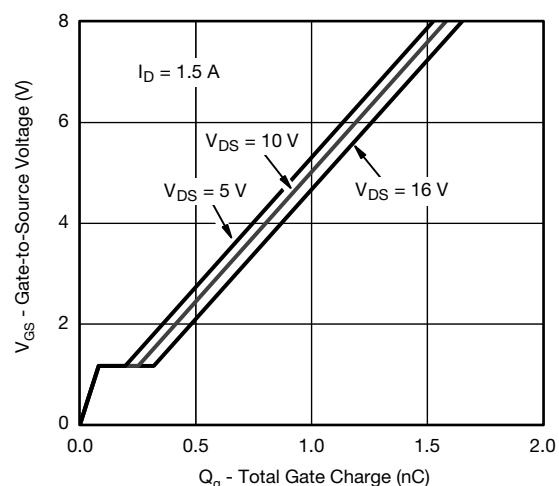
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		20		$\text{mV}/^\circ\text{C}$	
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 2.3			
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.5		2.0	V	
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$			± 25	μA	
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$			1		
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA	
		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			10		
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \leq 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	4			A	
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = 4.5 \text{ V}, I_D = 1 \text{ A}$		0.086		Ω	
		$V_{GS} = 2.5 \text{ V}, I_D = 1 \text{ A}$		0.110			
		$V_{GS} = 1.8 \text{ V}, I_D = 0.2 \text{ A}$		0.180			
Forward Transconductance ^a	g_{fs}	$V_{DS} = 4 \text{ V}, I_D = 1.5 \text{ A}$		4		S	
Dynamic^b							
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 8 \text{ V}, I_D = 1.5 \text{ A}$		5.0		nC	
Gate-Source Charge	Q_{gs}			3.0			
Gate-Drain Charge	Q_{gd}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 1.5 \text{ A}$		1.0			
Gate Resistance	R_g			2.0			
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 10 \text{ V}, R_L = 8.3 \Omega$ $I_D \geq 1.2 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		0.4	1.9	3.8	kΩ
Rise Time	t_r			43	65	ns	
Turn-Off Delay Time	$t_{d(\text{off})}$			80	120		
Fall Time	t_f			480	720		
Turn-on Delay Time	$t_{d(\text{on})}$	$V_{DD} = 10 \text{ V}, R_L = 8.3 \Omega$ $I_D \geq 1.2 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		220	330	ns	
Rise Time	tr			22	33		
Turn-Off Delay Time	$t_{d(\text{off})}$			46	70		
Fall Time	tr			645	968		
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$		2.6		A	
Pulse Diode Forward Current	I_{SM}			4			
Body Diode Voltage	V_{SD}	$I_S = 1.2 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V	
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 1.2 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		9	18	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			2	4	nC	
Reverse Recovery Fall Time	t_a			5		ns	
Reverse Recovery Rise Time	t_b			4			

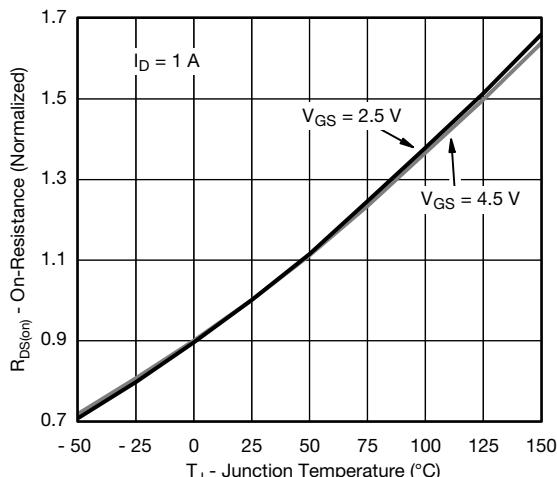
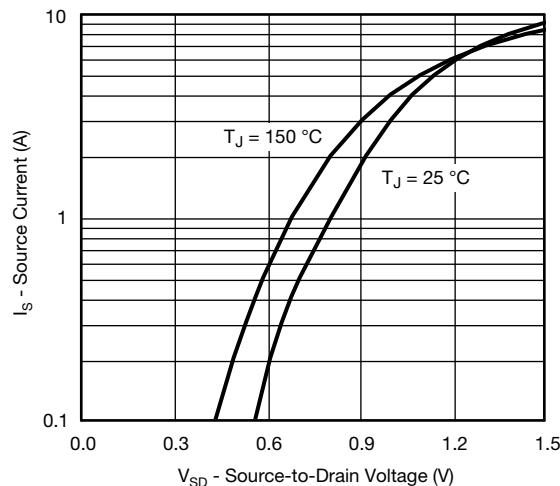
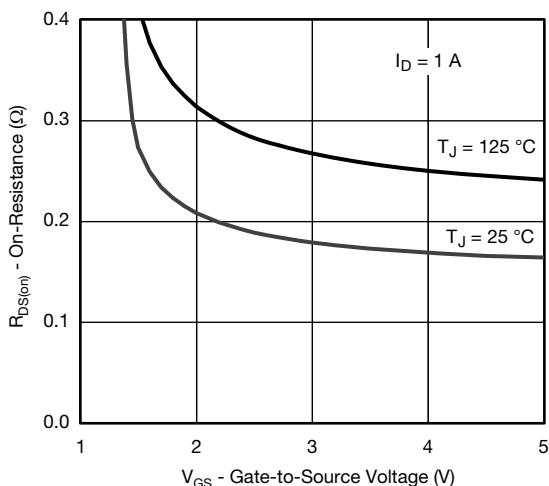
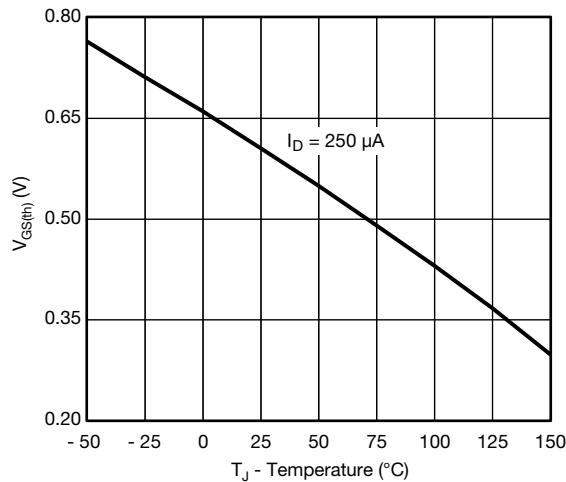
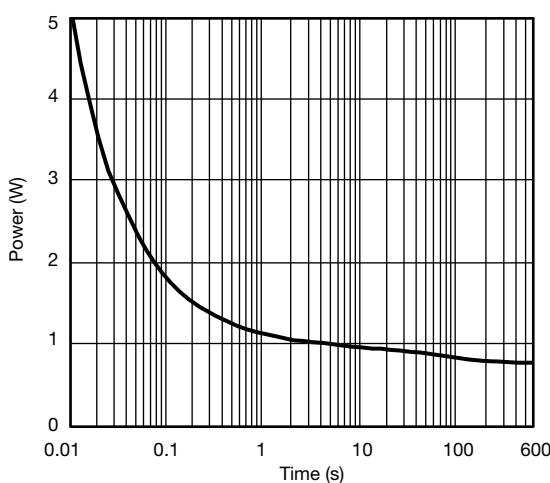
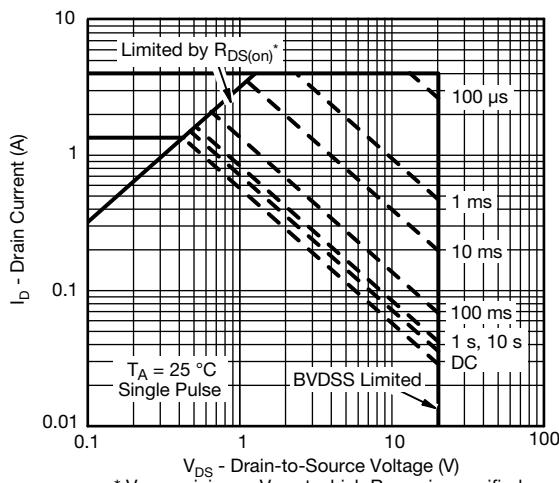
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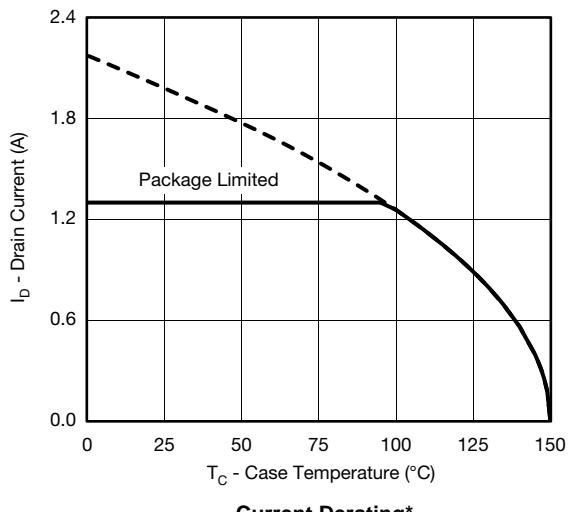
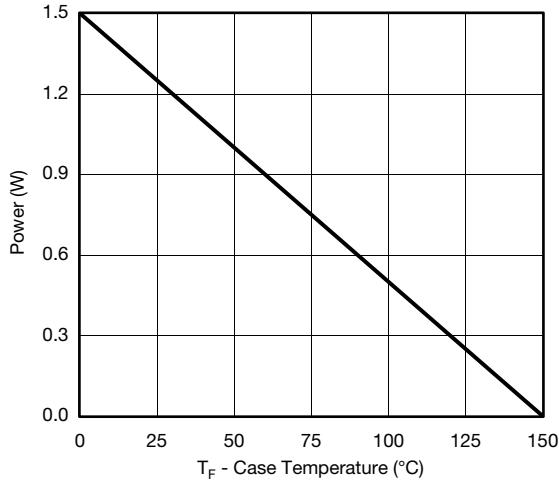
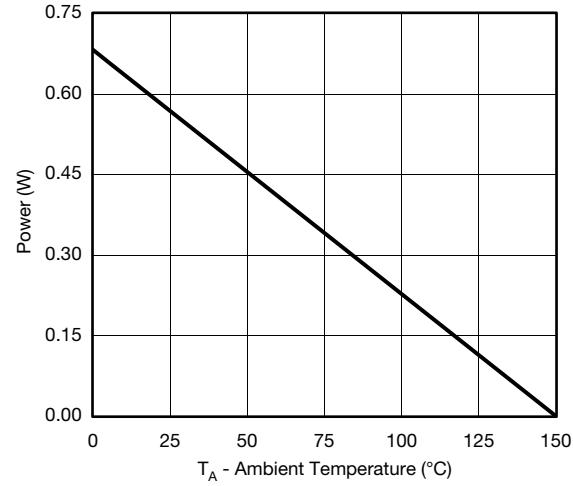
a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2 \%$.

b. Guaranteed by design, not subject to production testing.

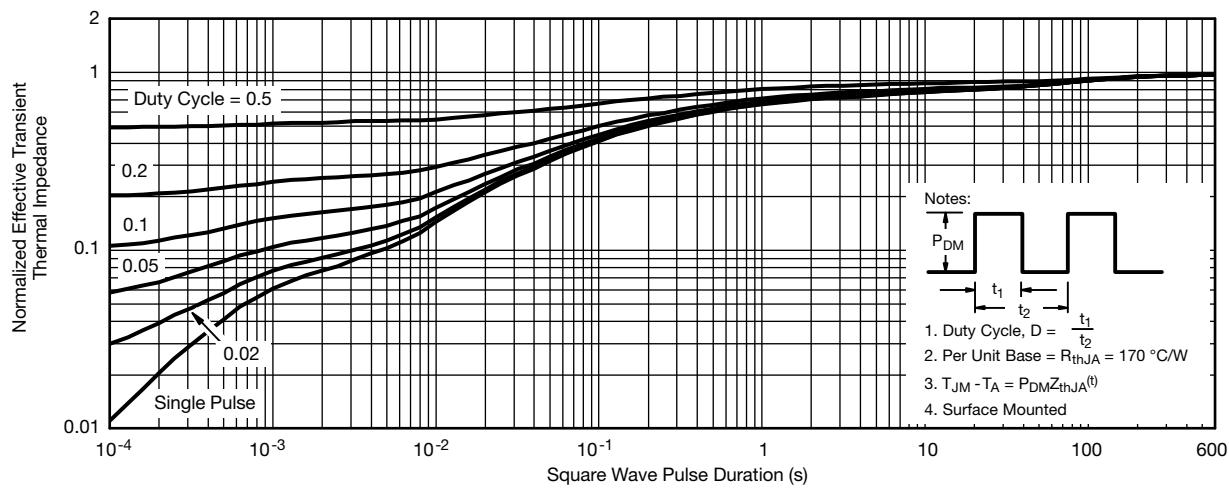
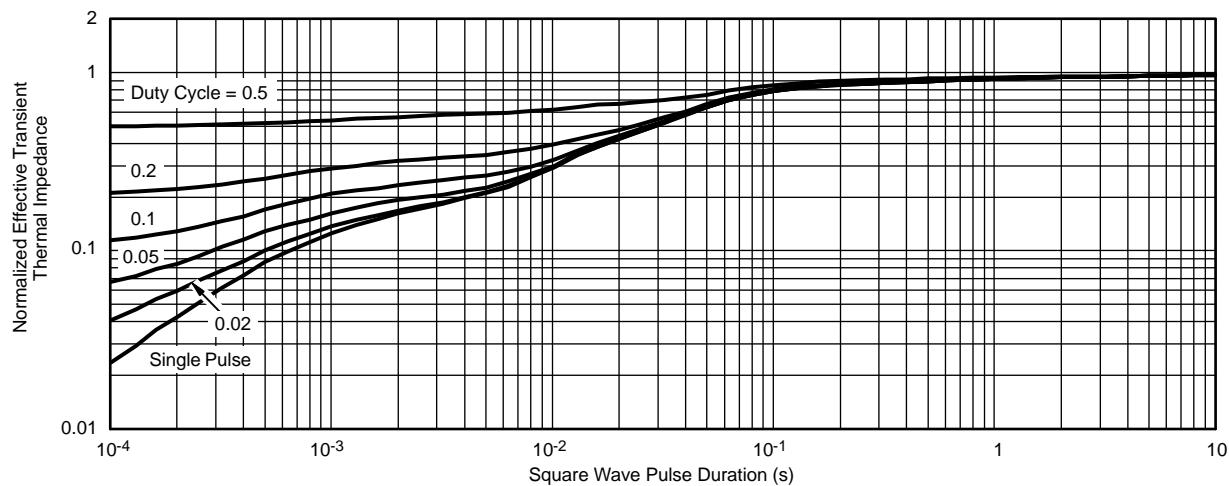
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Gate Current vs. Gate-to-Source Voltage

Gate Current vs. Gate-to-Source Voltage

Output Characteristics

Transfer Characteristics

On-Resistance vs. Drain Current

Gate Charge

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

On-Resistance vs. Junction Temperature

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage

Single Pulse Power, Junction-to-Ambient

Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Current Derating*

Power, Junction-to-Foot

Power, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Foot